

# 74ABT16952

## 16-Bit Registered Transceiver with 3-STATE Outputs

### General Description

The ABT16952 is a 16-bit registered transceiver. Two 8-bit back to back registers store data flowing in both directions between two bidirectional buses. Separate clock, clock enable and 3-STATE output enable signals are provided for each register. The output pins are guaranteed to source 32 mA and to sink 64 mA.

### Features

- Separate clock, clock enable and 3-STATE output enable provided for each register
- A and B output sink capability of 64 mA source capability of 32 mA
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Nondestructive hot insertion capability

### Ordering Code:

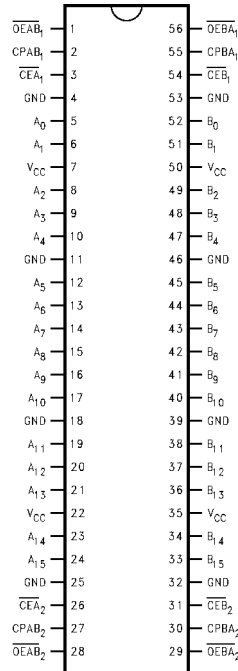
Order Number	Package Number	Package Description
74ABT16952CSSC	MS56A	56-Lead Shrink Small Outline Package (SSOP), JEDEC MO-118, 0.300" Wide
74ABT16952CMTD	MTD56	56-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide

Devices also available in Tape and Reel. Specify by appending the letter suffix "X" to the ordering code.

### Pin Descriptions

Pin Names	Description
A <sub>0</sub> -A <sub>15</sub>	Data Register A Inputs/ B-Register 3-STATE Outputs
B <sub>0</sub> -B <sub>15</sub>	Data Register B Inputs/ A-Register 3-STATE Outputs
CPAB <sub>n</sub> , CPBA <sub>n</sub>	Clock Pulse Inputs
CEA <sub>n</sub> , CEB <sub>n</sub>	Clock Enable
OEAB <sub>n</sub> , OEBA <sub>n</sub>	Output Enable Inputs

### Connection Diagram



### Output Control

OE	Internal Q	Output	Function
H	X	Z	Disable Outputs
L	L	L	Enable Outputs
L	H	H	

### Register Function Table

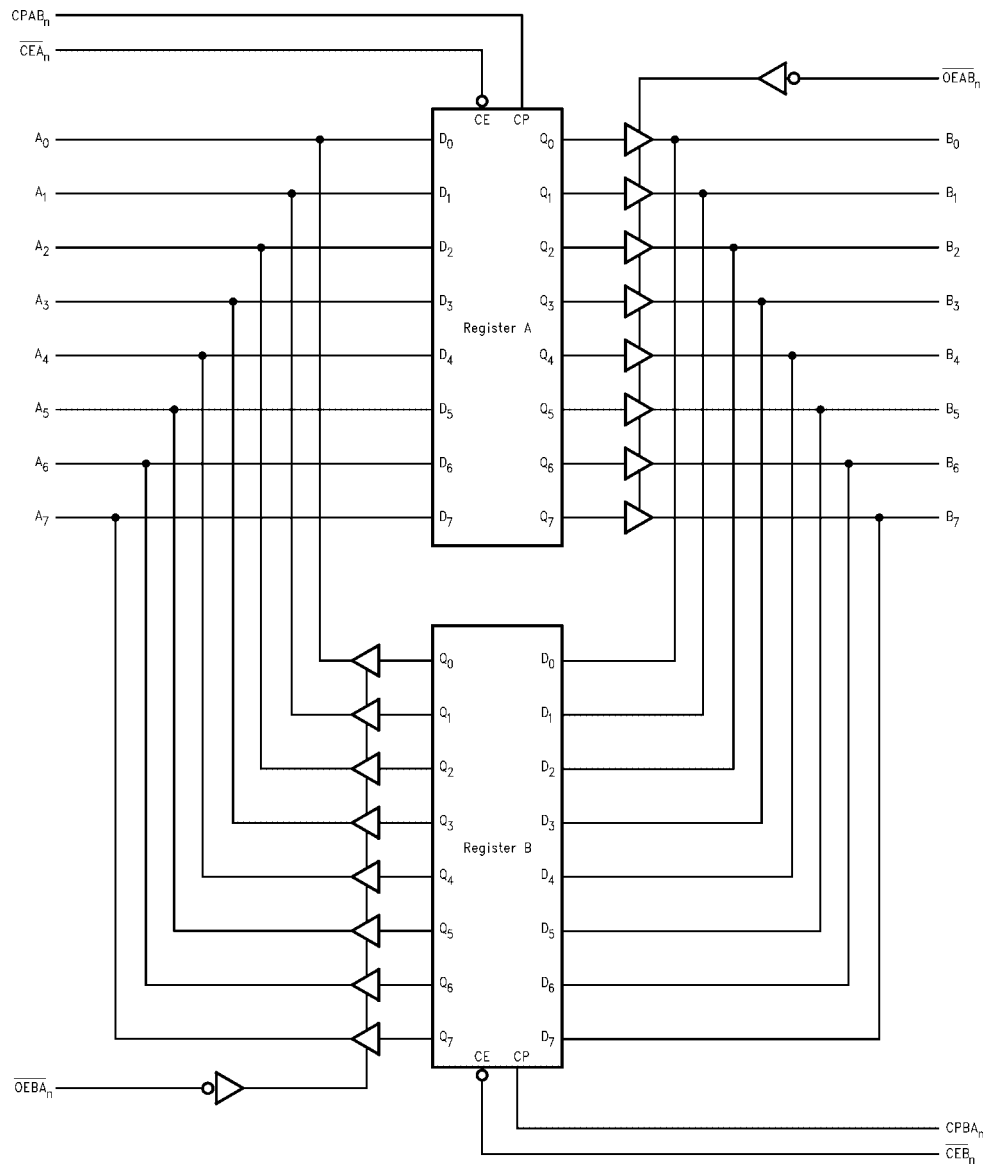
(Applies to A or B Register)

Inputs			Internal Q	Function
D	CP	CE		
X	X	H	NC	Hold Data
L	↗	L	L	Load Data
H	↗	L	H	

H = HIGH Voltage Level  
L = LOW Voltage Level  
X = Immaterial  
Z = HIGH Impedance  
↗ = LOW-to-HIGH Transition  
NC = No Change

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**Block Diagram**



n for either byte 1 or byte 2

**Absolute Maximum Ratings**(Note 1)

Storage Temperature	-65°C to +150°C
Ambient Temperature under Bias	-55°C to +125°C
Junction Temperature under Bias	-55°C to +150°C
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0 mA
Voltage Applied to Any Output in the Disable or Power-Off State	-0.5V to +5.5V
in the HIGH State	-0.5V to V <sub>CC</sub>
Current Applied to Output in LOW State (Max)	twice the rated I <sub>OL</sub> (mA)
DC Latchup Source Current	-500 mA
Over Voltage Latchup (I/O)	10V

**Recommended Operating Conditions**

Free Air Ambient Temperature	-40°C to +85°C
Supply Voltage	+4.5V to +5.5V
Minimum Input Edge Rate ( $\Delta V/\Delta t$ )	
Data Input	50 mV/ns
Enable Input	20 mV/ns
Clock Input	100 mV/ns

**Note 1:** Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

**Note 2:** Either voltage limit or current limit is sufficient to protect inputs.

**DC Electrical Characteristics**

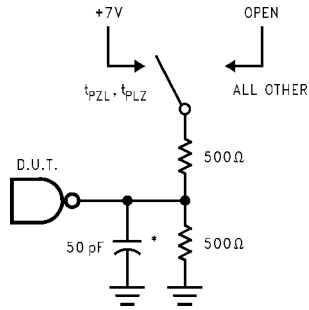
Symbol	Parameter	Min	Typ	Max	Units	V <sub>CC</sub>	Conditions
V <sub>IH</sub>	Input HIGH Voltage	2.0			V		Recognized HIGH Signal
V <sub>IL</sub>	Input LOW Voltage			0.8	V		Recognized LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltage			-1.2	V	Min	I <sub>IN</sub> = -18 mA (Non I/O Pins)
V <sub>OH</sub>	Output HIGH Voltage	2.5 2.0			V	Min	I <sub>OH</sub> = -3 mA (A <sub>n</sub> , B <sub>n</sub> ) I <sub>OH</sub> = -32 mA (A <sub>n</sub> , B <sub>n</sub> )
V <sub>OL</sub>	Output LOW Voltage			0.55	V	Min	I <sub>OL</sub> = 64 mA (A <sub>n</sub> , B <sub>n</sub> )
V <sub>ID</sub>	Input Leakage Test	4.75			V	0.0	I <sub>ID</sub> = 1.9 $\mu$ A (Non-I/O Pins) All Other Pins Grounded
I <sub>IH</sub>	Input HIGH Current			1 1	$\mu$ A	Max	V <sub>IN</sub> = 2.7V (Non-I/O Pins) (Note 4) V <sub>IN</sub> = V <sub>CC</sub> (Non-I/O Pins)
I <sub>BVI</sub>	Input HIGH Current Breakdown Test			7	$\mu$ A	Max	V <sub>IN</sub> = 7.0V (Non-I/O Pins)
I <sub>BVIT</sub>	Input HIGH Current Breakdown Test (I/O)			100	$\mu$ A	Max	V <sub>IN</sub> = 5.5V (A <sub>n</sub> , B <sub>n</sub> )
I <sub>IL</sub>	Input LOW Current			-1 -1	$\mu$ A	Max	V <sub>IN</sub> = 0.5V (Non-I/O Pins) (Note 4) V <sub>IN</sub> = 0.0V (Non-I/O Pins)
I <sub>IH</sub> + I <sub>OZH</sub>	Output Leakage Current			10	$\mu$ A	0V-5.5V	V <sub>OUT</sub> = 2.7V (A <sub>n</sub> , B <sub>n</sub> ); OEA or OEB = 2.0V
I <sub>IL</sub> + I <sub>OZL</sub>	Output Leakage Current			-10	$\mu$ A	0V-5.5V	V <sub>OUT</sub> = 0.5V (A <sub>n</sub> , B <sub>n</sub> ); OEA or OEB = 2.0V
I <sub>OS</sub>	Output Short-Circuit Current	-100		-275	mA	Max	V <sub>OUT</sub> = 0V (A <sub>n</sub> , B <sub>n</sub> )
I <sub>CEx</sub>	Output HIGH Leakage Current			50	$\mu$ A	Max	V <sub>OUT</sub> = V <sub>CC</sub> (A <sub>n</sub> , B <sub>n</sub> )
I <sub>ZZ</sub>	Bus Drainage Test			100	$\mu$ A	0.0V	V <sub>OUT</sub> = 5.5V (A <sub>n</sub> , B <sub>n</sub> ); All Others GND
I <sub>CCH</sub>	Power Supply Current			1.0	mA	Max	All Outputs HIGH
I <sub>CCL</sub>	Power Supply Current			60	mA	Max	All Outputs LOW
I <sub>CCZ</sub>	Power Supply Current			1.0	mA	Max	Outputs 3-STATE; All Others GND
I <sub>CCt</sub>	Additional I <sub>CC</sub> /Input			2.5	mA	Max	V <sub>I</sub> = V <sub>CC</sub> - 2.1V; All Others at V <sub>CC</sub> or GND
I <sub>CCD</sub>	Dynamic I <sub>CC</sub> (Note 4)	No Load		0.18	mA/ MHz	Max	Outputs OPEN OEA or OEB = GND, Non-I/O = GND or V <sub>CC</sub> One Bit toggling, 50% duty cycle (Note 3)

**Note 3:** For 8-bit toggling, I<sub>CCD</sub> < 1.4 mA/MHz.

**Note 4:** Guaranteed, but not tested.

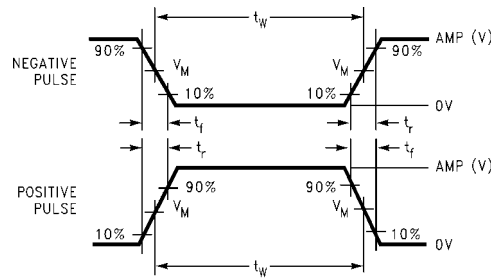
AC Electrical Characteristics						
(SSOP Package)						
Symbol	Parameter	$T_A = +25^\circ\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 50\text{ pF}$		$T_A = -40^\circ\text{C to } +85^\circ\text{C}$ $V_{CC} = 4.5\text{V to } 5.5\text{V}$ $C_L = 50\text{ pF}$		Units
		Min	Max	Min	Max	
$f_{\text{MAX}}$	Maximum Clock Frequency	200		200		MHz
$t_{\text{PLH}}$	Propagation Delay	1.5	5.3	1.5	5.3	ns
$t_{\text{PHL}}$	$\overline{\text{CPAB}}_n$ or $\overline{\text{CPBA}}_n$ to $A_n$ or $B_n$	1.5	5.3	1.5	5.3	
$t_{\text{PZH}}$	Output Enable Time	1.5	5.5	1.5	5.5	ns
$t_{\text{PZL}}$	$\overline{\text{OEAB}}_n$ or $\overline{\text{OEBA}}_n$ to $A_n$ or $B_n$	1.5	5.5	1.5	5.5	
$t_{\text{PHZ}}$	Output Disable Time	1.5	6.0	1.5	6.0	ns
$t_{\text{PLZ}}$	$\overline{\text{OEAB}}_n$ or $\overline{\text{OEBA}}_n$ to $A_n$ or $B_n$	1.5	6.0	1.5	6.0	
AC Operating Requirements						
Symbol	Parameter	$T_A = +25^\circ\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 50\text{ pF}$		$T_A = -40^\circ\text{C to } +85^\circ\text{C}$ $V_{CC} = 4.5\text{V to } 5.5\text{V}$ $C_L = 50\text{ pF}$		Units
		Min	Max	Min	Max	
$t_{\text{S}}(\text{H})$	Setup Time, HIGH	2.5		2.5		ns
$t_{\text{S}}(\text{L})$	or LOW $A_n$ or $B_n$ to $\overline{\text{CPAB}}_n$ or $\overline{\text{CPBA}}_n$	2.5		2.5		
$t_{\text{H}}(\text{H})$	Hold Time, HIGH	1.5		1.5		ns
$t_{\text{H}}(\text{L})$	or LOW $A_n$ or $B_n$ to $\overline{\text{CPAB}}_n$ or $\overline{\text{CPBA}}_n$	1.5		1.5		
$t_{\text{S}}(\text{H})$	Setup Time, HIGH	2.5		2.5		ns
$t_{\text{S}}(\text{L})$	or LOW $\overline{\text{CEA}}_n$ or $\overline{\text{CEB}}_n$ to $\overline{\text{CPAB}}_n$ or $\overline{\text{CPBA}}_n$	2.5		2.5		
$t_{\text{H}}(\text{H})$	Hold Time, HIGH	1.5		1.5		ns
$t_{\text{H}}(\text{L})$	or LOW $\overline{\text{CEA}}_n$ or $\overline{\text{CEB}}_n$ to $\overline{\text{CPAB}}_n$ or $\overline{\text{CPBA}}_n$	1.5		1.5		
$t_{\text{W}}(\text{H})$	Pulse Width, HIGH	3.0		3.0		ns
$t_{\text{W}}(\text{L})$	or LOW to $\overline{\text{CPAB}}_n$ or $\overline{\text{CPBA}}_n$	3.0		3.0		
Capacitance						
Symbol	Parameter	Typ	Units	Conditions $T_A = 25^\circ\text{C}$		
$C_{\text{IN}}$	Input Capacitance	5	pF	$V_{CC} = 0\text{V}$ (Non I/O Pins)		
$C_{\text{IO}}$ (Note 5)	Output Capacitance	11	pF	$V_{CC} = 5.0\text{V}$ ( $A_n$ , $B_n$ )		
<b>Note 5:</b> $C_{\text{IO}}$ is measured at frequency $f = 1\text{ MHz}$ , per MIL-STD-883, Method 3012.						

**AC Loading**



\*Includes jig and probe capacitance

**FIGURE 1. Standard AC Test Load**



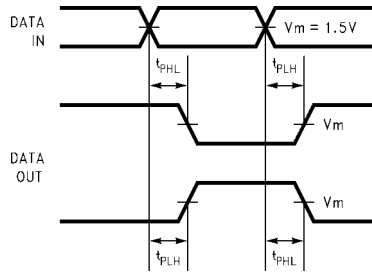
$V_M = 1.5V$

**FIGURE 2. Test Input Signal Levels**

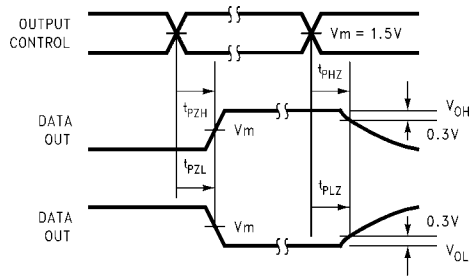
Amplitude	Rep. Rate	$t_w$	$t_r$	$t_f$
3.0V	1 MHz	500 ns	2.5 ns	2.5 ns

**FIGURE 3. Input Signal Requirements**

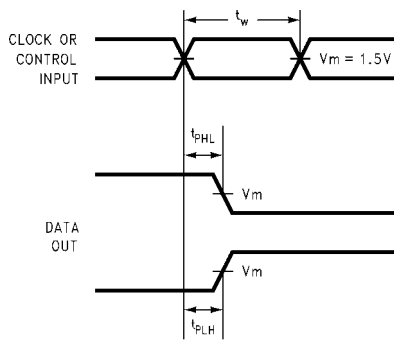
**AC Waveforms**



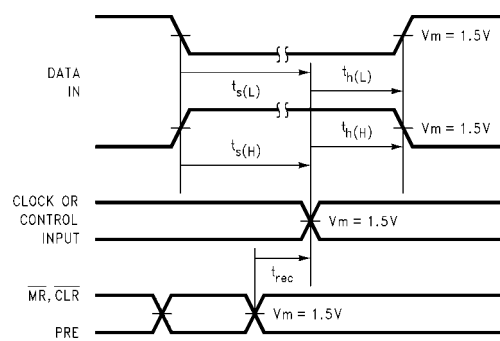
**FIGURE 4. Propagation Delay Waveforms for Inverting and Non-Inverting Functions**



**FIGURE 6. 3-STATE Output HIGH and LOW Enable and Disable Times**

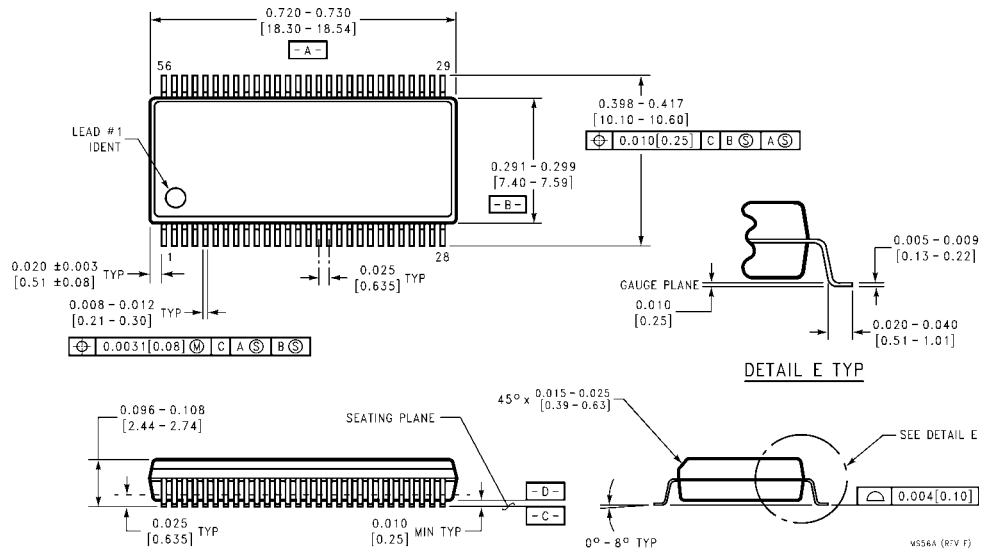


**FIGURE 5. Propagation Delay, Pulse Width Waveforms**



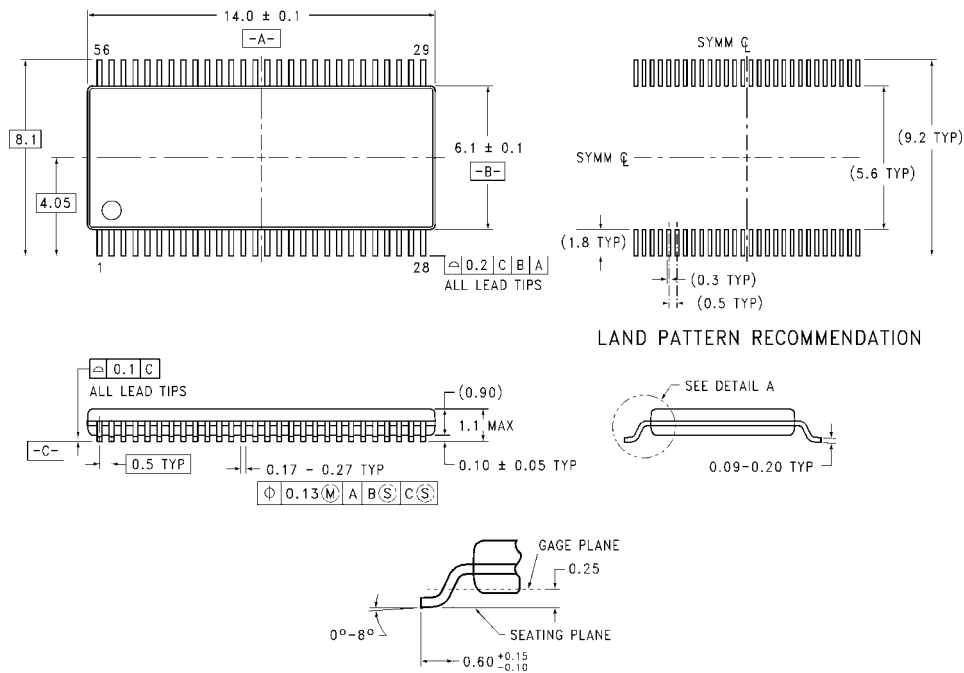
**FIGURE 7. Setup Time, Hold Time and Recovery Time Waveforms**

**Physical Dimensions** inches (millimeters) unless otherwise noted



**56-Lead Shrink Small Outline Package (SSOP), JEDEC MO-118, 0.300" Wide  
Package Number MS56A**

**Physical Dimensions** inches (millimeters) unless otherwise noted (Continued)



**56-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide  
Package Number MTD56**

MTD56 (REV B)

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